Unit Loading/Fan Out

Pin Names	Donasistics.	U.L.	Input I _{IH} /I _{IL}		
	Description	HIGH/LOW	Output I _{OH} /I _{OL}		
S	Common Data Select Input	1.0/1.0	20 μA/-0.6 mA		
ŌĒ	3-STATE Output Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA		
$I_{0a}-I_{0d}$	Data Inputs from Source 0	1.0/1.0	20 μA/-0.6 mA		
I _{1a} –I _{1d}	Data Inputs from Source 1	1.0/1.0	20 μA/-0.6 mA		
Z _a –Z _d	3-STATE Multiplexer Outputs	150/40 (33.3)	-3 mA/24 mA (20 mA)		

Truth Table

	Output	Select	Da	ata	Output	
Enable		Input	Inputs		Output	
	ŌĒ	s	I ₀	I ₁	z	
	Н	Х	Х	Х	Z	
	L	Н	Х	L	L	
	L	Н	Х	Н	Н	
	L	L	L	Χ	L	
	L	L	Н	X	Н	

H = HIGH Voltage Level L = LOW Voltage Level

- X = Immaterial Z = High Impedance

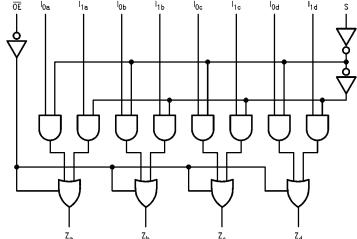
Functional Description

The 74F257A is a quad 2-input multiplexer with 3-STATE outputs. It selects four bits of data from two sources under control of a Common Data Select input. When the Select input is LOW, the I_{0x} inputs are selected and when Select $\,$ is HIGH, the I_{1x} inputs are selected. The data on the selected inputs appears at the outputs in true (noninverted) form. The device is the logic implementation of a 4-pole, 2-position switch where the position of the switch is determined by the logic levels supplied to the Select input. The logic equation for the outputs is shown below:

$$Z_n = \overline{OE} \bullet (I_n \bullet S + I_{on} \bullet \overline{S})$$

When the Output Enable input (\overline{OE}) is HIGH, the outputs are forced to a high impedance OFF state. If the outputs are tied together, all but one device must be in the high impedance state to avoid high currents that would exceed the maximum ratings. Designers should ensure the Output Enable signals to 3-STATE devices whose outputs are tied together are designed so there is no overlap.

Logic Diagram



 $Z_{a} \qquad \qquad Z_{b} \qquad \qquad Z_{c} \qquad \qquad Z_{d}$ Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 1)

Recommended Operating Conditions

 $\begin{array}{ll} \mbox{Storage Temperature} & -65^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to } +125^{\circ}\mbox{C} \\ \end{array}$

Junction Temperature under Bias -55° C to $+150^{\circ}$ C V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V

Voltage Applied to Output in HIGH State (with $V_{CC} = 0V$)

 $\begin{array}{ll} \text{Standard Output} & -0.5 \text{V to V}_{\text{CC}} \\ \text{3-STATE Output} & -0.5 \text{V to +5.5V} \end{array}$

Current Applied to Output

 $\label{eq:lower_lower} \begin{array}{ll} \text{in LOW State (Max)} & \text{twice the rated I}_{\text{OL}} \ (\text{mA}) \\ \text{ESD Last Passing Voltage (Min)} & 4000 \text{V} \end{array}$

Free Air Ambient Temperature $0^{\circ}\text{C} \text{ to } +70^{\circ}\text{C}$ Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

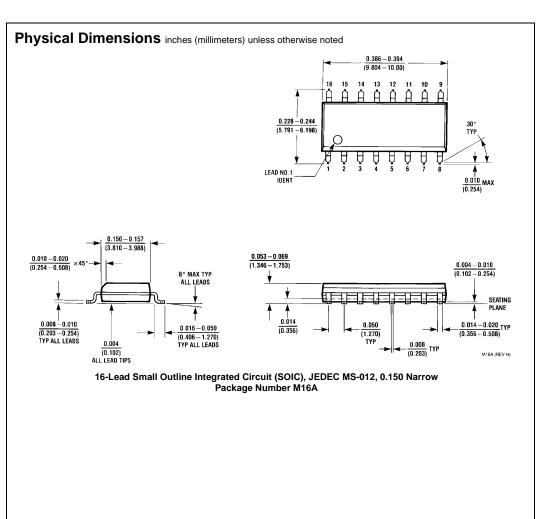
DC Electrical Characteristics

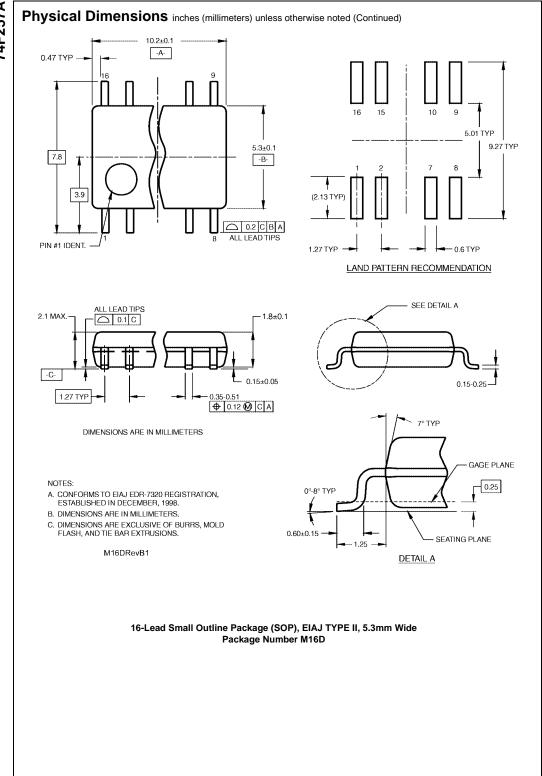
Symbol	Paramete	r	Min	Тур	Max	Units	V _{CC}	Conditions
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	I _{IN} = -18 mA
V _{OH}	Output HIGH	10% V _{CC}	2.5					I _{OH} = -1 mA
	Voltage	10% V _{CC}	2.4			V	Min	$I_{OH} = -3 \text{ mA}$
		$5\% V_{CC}$	2.7			•	IVIIII	$I_{OH} = -1 \text{ mA}$
		$5\% V_{CC}$	2.7					$I_{OH} = -3 \text{ mA}$
V _{OL}	Output LOW Voltage	10% V _{CC}			0.5	V	Min	I _{OL} = 24 mA
I _{IH}	Input HIGH				5.0	μA Max		V _{IN} = 2.7V
	Current				5.0	μА	IVIAA	V N - 2.1 V
I _{BVI}	Input HIGH Current				7.0	μА	Max	V _{IN} = 7.0V
	Breakdown Test				7.0	μΛ	IVIAA	V N = 1.0V
I _{CEX}	Output HIGH				50	μА	Max	V _{OUT} = V _{CC}
	Leakage Current				30	μΛ	iviax	VOUT - VCC
V_{ID}	Input Leakage		4.75			V	0.0	I _{ID} = 1.9 μA
	Test		4.73			V	0.0	All Other Pins Grounded
I _{OD}	Output Leakage				3.75	μА	0.0	V _{IOD} = 150 mV
	Circuit Current				3.73	μΛ	0.0	All Other Pins Grounded
I _{IL}	Input LOW Current				-0.6	mA	Max	V _{IN} = 0.5V
I _{OZH}	Output Leakage Current				50	μΑ	Max	V _{OUT} = 2.7V
l _{OZL}	Output Leakage Current				-50	μΑ	Max	V _{OUT} = 0.5V
los	Output Short-Circuit Curre	ent	-60		-150	mA	Max	V _{OUT} = 0V
I _{ZZ}	Bus Drainage Test				500	μΑ	0.0V	V _{OUT} = 5.25V
I _{CCH}	Power Supply Current			9.0	15	mA	Max	V _O = HIGH
I _{CCL}	Power Supply Current			14.5	22	mA	Max	$V_O = LOW$
I _{CCZ}	Power Supply Current			15	23	mA	Max	V _O = HIGH Z

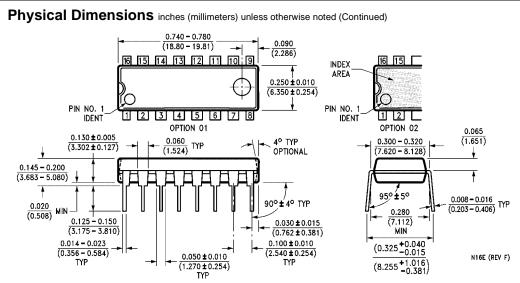
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AC Electrical Characteristics

Symbol	Parameter	$T_{A} = +25^{\circ}C$ $V_{CC} = 5.0V$ $C_{L} = 50 \text{ pF}$			$T_{A} = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = 5.0V$ $C_{L} = 50 \text{ pF}$		$T_A = 0$ °C to +70°C $V_{CC} = 5.0$ V $C_L = 50$ pF		Units
		Min	Тур	Max	Min	Max	Min	Max	
t _{PLH}	Propagation Delay	2.5	4.5	5.5	2.0	7.0	2.0	6.0	20
t _{PHL}	I _n to Z _n	2.0	4.2	5.5	1.5	7.0	2.0	6.0	ns
t _{PLH}	Propagation Delay	4.0	5.0	9.5	3.5	11.5	3.5	10.5	ns
t _{PHL}	S to Z _n	2.5	6.5	7.0	2.5	9.0	2.5	8.0	115
t _{PZH}	Output Enable Time	2.0	5.9	6.0	2.0	8.0	2.0	7.0	
t _{PZL}		2.5	5.5	7.0	2.5	9.0	2.5	8.0	ns
t _{PHZ}	Output Disable Time	2.0	4.3	6.0	2.0	7.0	2.0	7.0	115
t _{PLZ}		2.0	4.5	6.0	2.0	8.5	2.0	7.0	







16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N16E

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